

**TC74HC4094AP, TC74HC4094AF, TC74HC4094AFN**

**8 - BIT SHIFT AND STORE REGISTER (3 - STATE)**

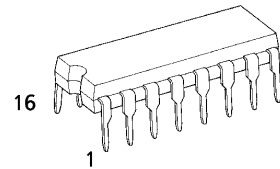
The TC74HC4094A is a high speed CMOS 8-BIT SHIFT AND STROBE REGISTER fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. It consists of an 8-bit shift register and an 8-bit latch with 3-state output buffers. Data is shifted serially through the shift register on the positive going transition of the CK input. The output of the last stage (Qs) can be used to cascade several devices. Data on the Qs output is transferred to a second output (Q's) on the following negative transition of the CK input. The data in each stage of the shift register is provided to a corresponding latch, on the negative going transition of the STROBE input. When STROBE is held high, data propagates through the latch to a 3-state output buffer. This buffer is enabled when OUTPUT ENABLE input is set high. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

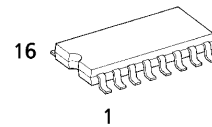
**FEATURES :**

- High Speed..... $f_{MAX} = 73\text{MHz}(\text{typ.})$  at  $V_{CC} = 5\text{V}$
- Low Power Dissipation..... $I_{CC} = 4\mu\text{A}(\text{Max.})$  at  $T_a = 25^\circ\text{C}$
- High Noise Immunity..... $V_{NIH} = V_{NIL} = 28\% V_{CC} (\text{Min.})$
- Output Drive Capability ..... 10 LSTTL Loads
- Symmetrical Output Impedance...  $|I_{OH}| = I_{OL} = 4\text{mA}(\text{Min.})$
- Balanced Propagation Delays.....  $t_{PLH} \approx t_{PHL}$
- Wide Operating Voltage Range...  $V_{CC} (\text{opr.}) = 2\text{V} \sim 6\text{V}$
- Pin and Function Compatible with 4094B

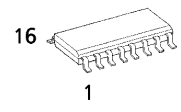
(Note) The JEDEC SOP (FN) is not available in Japan.



P (DIP16-P-300-2.54A)  
Weight : 1.00g (Typ.)

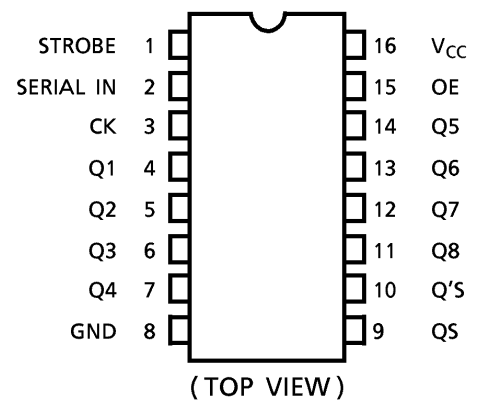


F (SOP16-P-300-1.27)  
Weight : 0.18g (Typ.)

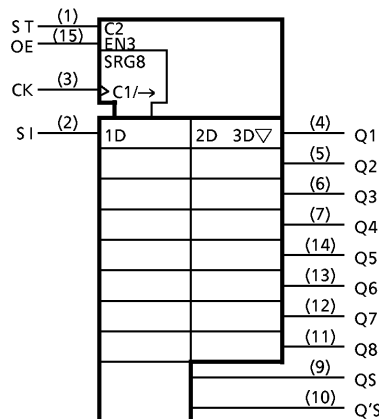


FN (SOL16-P-150-1.27)  
Weight : 0.13g (Typ.)

**PIN ASSIGNMENT**



**IEC LOGIC SYMBOL**

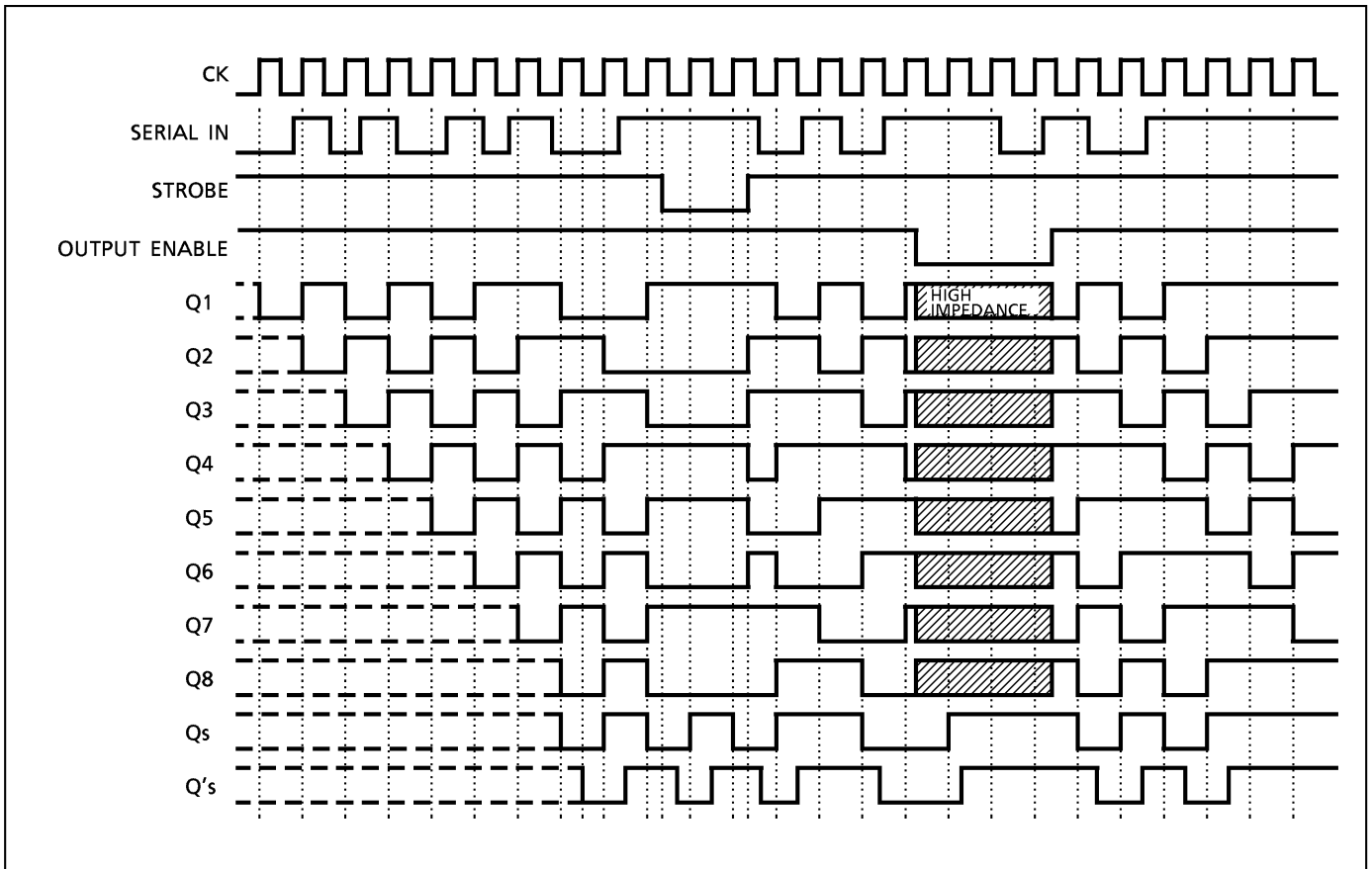


**TRUTH TABLE**

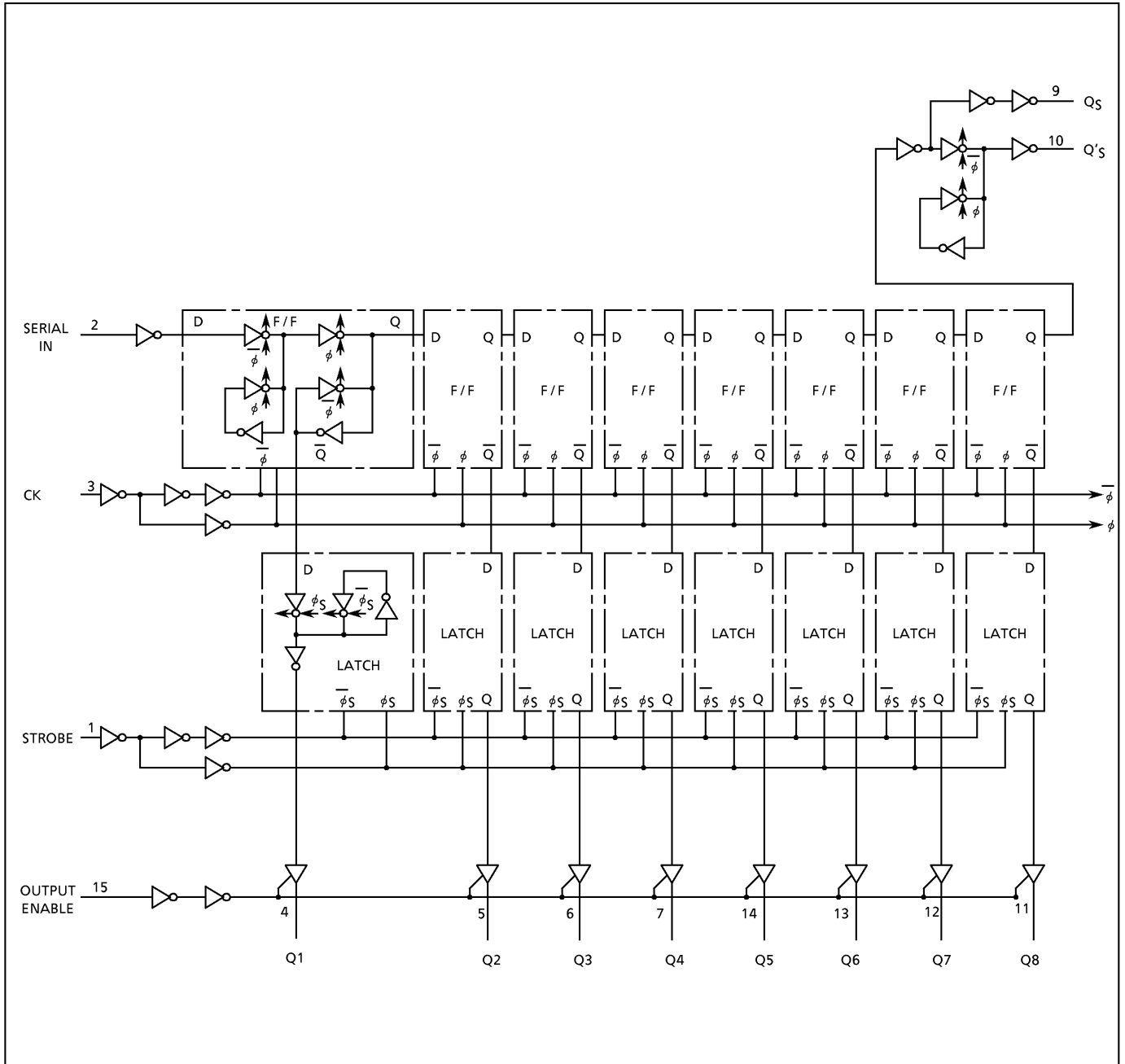
CK	OE	ST	SI	PARA. OUT		SERI. OUT	
				Q1	Qn	Qs	Q's
	H	H	L	L	Qn - 1	Q7	NC
	H	H	H	H	Qn - 1	Q7	NC
	H	L	*	NC	NC	Q7	NC
	L	*	*	Z	Z	Q7	NC
	H	*	*	NC	NC	NC	Qs
	L	*	*	Z	Z	NC	Qs

X : DON'T CARE  
 NC : NO CHANGE  
 Z : HIGH IMPEDANCE

**TIMING CHART**



SYSTEM DIAGRAM



## ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	$V_{CC}$	-0.5~7	V
DC Input Voltage	$V_{IN}$	-0.5~ $V_{CC} + 0.5$	V
DC Output Voltage	$V_{OUT}$	-0.5~ $V_{CC} + 0.5$	V
Input Diode Current	$I_{IK}$	± 20	mA
Output Diode Current	$I_{OK}$	± 20	mA
DC Output Current	$I_{OUT}$	± 25	mA
DC $V_{CC}$ / Ground Current	$I_{CC}$	± 50	mA
Power Dissipation	$P_D$	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	$T_{stg}$	-65~150	°C

\*500mW in the range of  $T_a = -40^{\circ}\text{C} \sim 65^{\circ}\text{C}$ . From  $T_a = 65^{\circ}\text{C}$  to  $85^{\circ}\text{C}$  a derating factor of  $-10\text{mW}/^{\circ}\text{C}$  shall be applied until 300mW.

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	$V_{CC}$	2~6	V
Input Voltage	$V_{IN}$	0~ $V_{CC}$	V
Output Voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating Temperature	$T_{opr}$	-40~85	°C
Input Rise and Fall Time	$t_r, t_f$	0~ 1000 ( $V_{CC} = 2.0\text{V}$ ) 0~ 500 ( $V_{CC} = 4.5\text{V}$ ) 0~ 400 ( $V_{CC} = 6.0\text{V}$ )	ns

## DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}$ (V)	$T_a = 25^{\circ}\text{C}$			$T_a = -40 \sim 85^{\circ}\text{C}$		UNIT	
				MIN.	TYP.	MAX.	MIN.	MAX.		
High - Level Input Voltage	$V_{IH}$		2.0	1.50	—	—	1.50	—	V	
			4.5	3.15	—	—	3.15	—		
			6.0	4.20	—	—	4.20	—		
Low - Level Input Voltage	$V_{IL}$		2.0	—	—	0.50	—	0.50	V	
			4.5	—	—	1.35	—	1.35		
			6.0	—	—	1.80	—	1.80		
High - Level Output Voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -20\mu\text{A}$	2.0	1.9	2.0	—	1.9	V	
				4.5	4.4	4.5	—	4.4		—
			$I_{OH} = -4\text{ mA}$ $I_{OH} = -5.2\text{ mA}$	4.5	4.18	4.31	—	4.13	—	
				6.0	5.68	5.80	—	5.63		—
Low - Level Output Voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 20\mu\text{A}$	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
			$I_{OL} = 4\text{ mA}$ $I_{OL} = 5.2\text{ mA}$	4.5	—	0.17	0.26	—	0.33	—
				6.0	—	0.18	0.26	—	0.33	
3 - State Output Off - State Current	$I_{OZ}$	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND	6.0	—	—	± 0.5	—	± 5.0	$\mu\text{A}$	
Input Leakage Current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	± 0.1	—	± 1.0		
Quiescent Supply Current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND	6.0	—	—	4.0	—	40.0		

TIMING REQUIREMENTS (Input  $t_r = t_f = 6\text{ns}$ )

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}$ (V)	$T_a = 25^\circ\text{C}$		$T_a = -40\text{--}85^\circ\text{C}$	UNIT
				TYP.	LIMIT	LIMIT	
Minimum Pulse Width (CK)	$t_{W(H)}$ $t_{W(L)}$		2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Pulse Width (STROBE)	$t_{W(H)}$		2.0	—	75	95	
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Set-up Time (SERIAL)	$t_s$		2.0	—	75	95	
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Set-up Time (STROBE)	$t_s$		2.0	—	100	125	
			4.5	—	20	25	
			6.0	—	17	21	
Minimum Hold Time (SERIAL)	$t_h$		2.0	—	0	0	
			4.5	—	0	0	
			6.0	—	0	0	
Minimum Hold Time (STROBE)	$t_h$		2.0	—	0	0	
			4.5	—	0	0	
			6.0	—	0	0	
Clock Frequency	f		2.0	—	6	5	MHz
			4.5	—	30	24	
			6.0	—	35	28	

**AC ELECTRICAL CHARACTERISTICS (  $C_L = 15\text{pF}$ ,  $V_{CC} = 5\text{V}$ ,  $T_a = 25^\circ\text{C}$ , Input  $t_r = t_f = 6\text{ns}$  )**

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition Time	$t_{TLH}$ $t_{THL}$		—	4	8	ns
Propagation Delay Time (CK—Qn)	$t_{pLH}$ $t_{pHL}$		—	22	35	
Propagation Delay Time (CK—QS, Q'S)	$t_{pLH}$ $t_{pHL}$		—	16	25	
Propagation Delay Time (STROBE—Qn)	$t_{pLH}$ $t_{pHL}$		—	16	27	
3-State Output Enable Time	$t_{pZL}$ $t_{pZH}$	$R_L = 1\text{K}\Omega$	—	13	25	
Maximum Clock Frequency	$f_{MAX}$		33	73	—	MHz

**AC ELECTRICAL CHARACTERISTICS (  $C_L = 50\text{pF}$ , Input  $t_r = t_f = 6\text{ns}$  )**

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}$ (V)	$T_a = 25^\circ\text{C}$			$T_a = -40\sim 85^\circ\text{C}$		UNIT
				MIN.	TYP.	MAX.	MIN.	MAX.	
Output Transition Time	$t_{TLH}$ $t_{THL}$		2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation Delay Time (CK—Qn)	$t_{pLH}$ $t_{pHL}$		2.0	—	92	200	—	250	
			4.5	—	26	40	—	50	
			6.0	—	20	34	—	43	
Propagation Delay Time (CK—QS, Q'S)	$t_{pLH}$ $t_{pHL}$		2.0	—	65	150	—	190	
			4.5	—	19	30	—	38	
			6.0	—	15	26	—	32	
Propagation Delay Time (STROBE—Qn)	$t_{pLH}$ $t_{pHL}$		2.0	—	75	160	—	200	
			4.5	—	20	32	—	40	
			6.0	—	16	27	—	34	
3-State Output Enable Time	$t_{pZL}$ $t_{pZH}$	$R_L = 1\text{K}\Omega$	2.0	—	58	150	—	190	
			4.5	—	16	30	—	38	
			6.0	—	13	26	—	32	
3-State Output Disable Time	$t_{pLZ}$ $t_{pHZ}$	$R_L = 1\text{K}\Omega$	2.0	—	35	150	—	190	
			4.5	—	16	30	—	38	
			6.0	—	13	26	—	32	
Maximum Clock Frequency	$f_{MAX}$		2.0	6	16	—	5	—	MHz
			4.5	30	66	—	24	—	
			6.0	35	80	—	28	—	
Input Capacitance	$C_{IN}$			—	5	10	—	10	pF
Bus Input Capacitance	$C_{OUT}$			—	10	—	—	—	
Power Dissipation Capacitance	$C_{PD} (1)$			—	140	—	—	—	

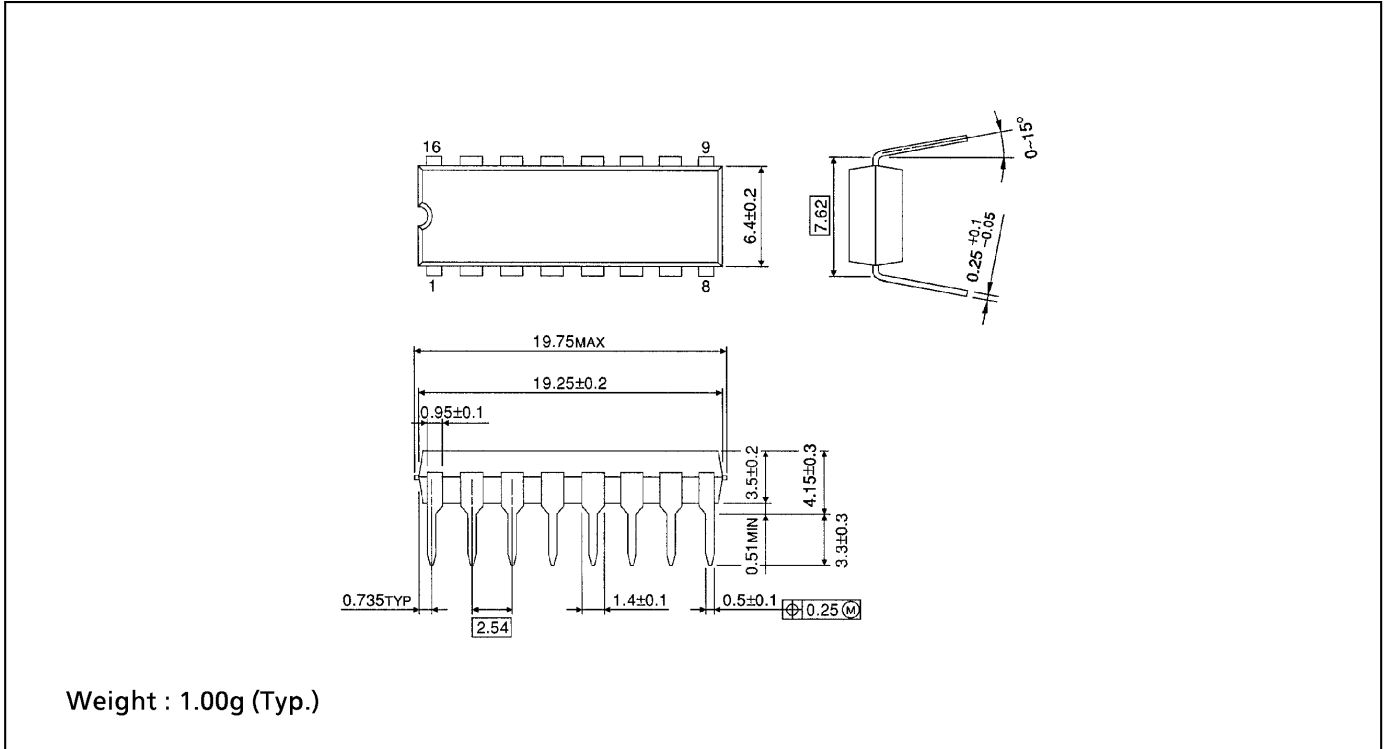
Note (1)  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

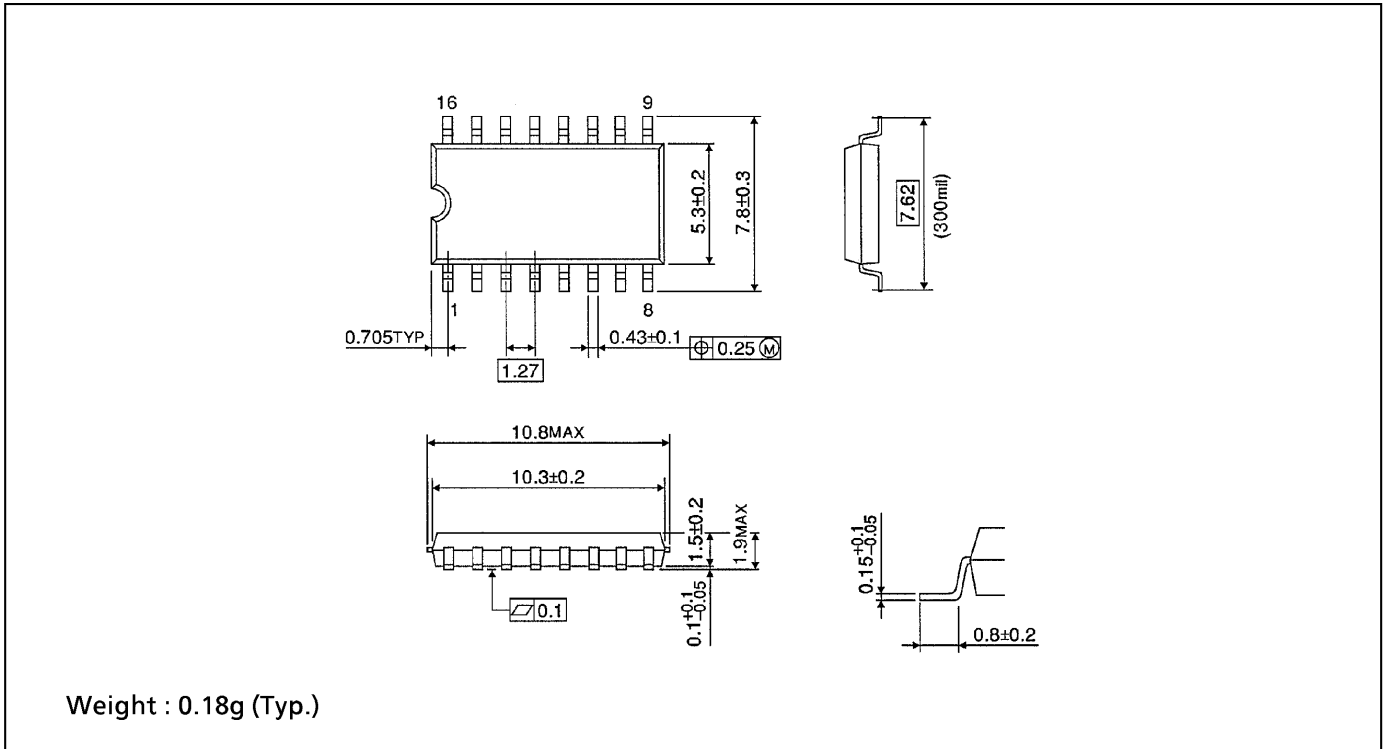
**DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)**

Unit in mm



**SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)**

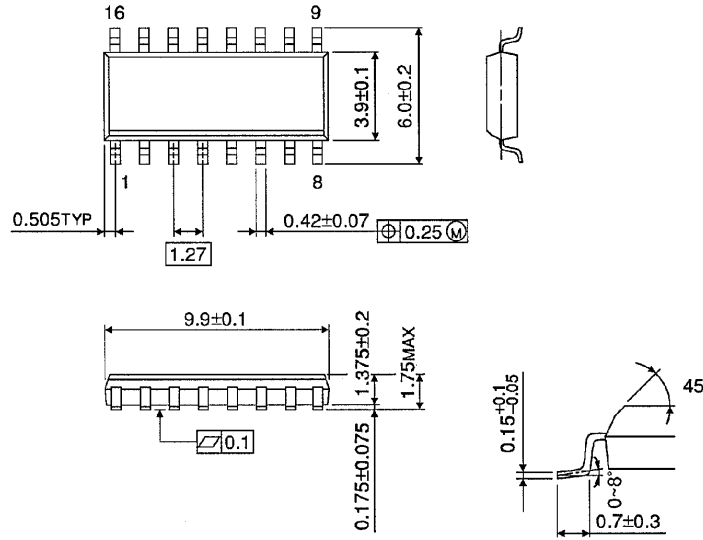
Unit in mm



**SOP 16PIN (150mil BODY) PACKAGE DIMENSIONS (SOL16-P-150 -1.27)**

Unit in mm

(Note) This package is not available in Japan.



Weight : 0.13g (Typ.)



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